



NCP2815BFCT2GEVB:NOCAP Headphone Amplifier **Evaluation Board**

Evaluation Board Description

NCP2815 is a dual LongPlay true ground headphone amplifier designed for portable communication device applications such as mobile phones. This part is capable of delivering 26 mW of continuous average power into a 32Ω load from a 1.8 V power supply with a THD+N of 1%

Based on the power supply delivered to the device, an internal power management block generates a symmetrical positive and negative voltage. Thus, the internal amplifiers provide outputs referenced to



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Ground and the losses are reduced which helps to increase the battery life. In this NOCAP configuration, the two external heavy coupling capacitors can be removed. This provides a significant space and cost savings compared to a typical stereo application.

This evaluation board showcases the B version of the part with and internal gain of -1.5 V/V. It reaches a superior -100 dB PSRR and noise floor. Thus, it offers high fidelity audio sound, as well as a direct connection to the battery. It contains circuitry to prevent "Pop & Click" noise that would otherwise occur during turn-on and turn-off transitions. The device is available in 12 bump CSP package (1.2 x 1.6 mm) which helps to save space on the board.

Evaluation Board Information

Evaluation Board	Status		Short Description	Parts Used	Action
NCP2815BFCT2GEVB	Active	P6)	NOCAP Headphone Amplifier Evaluation Board	NCP2815BFCT2G	

Technica	echnical Documents					
Туре	Document Title	Document ID/Size				
Eval Board: BOM	NCP2815BFCT2GEVB Bill of Materials ROHS Compliant	NCP2815BFCT2GEVB_BOM_ROHS.PDF - 103.0 KB	0			
Eval Board: Gerber	NCP2815BFCT2GEVB Gerber Layout Files (Zip Format)	NCP2815BFCT2GEVB_GERBER.ZIP - 156.0 KB	0			
Eval Board: Schematic	NCP2815BFCT2GEVB Schematic	NCP2815BFCT2GEVB_SCHEMATIC.PDF - 126.0 KB	0			
Eval Board: Test Procedure	NCP2815BFCT2GEVB Test Procedure	NCP2815BFCT2GEVB_TEST_PROCEDURE.PDF - 168.0 KB	0			

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